


<b>Search Notes</b>  	<b>Application/Control No.</b>  10501315	<b>Applicant(s)/Patent Under Reexamination</b>  TO, BAN CHIN
	<b>Examiner</b>  Makiya, David J	<b>Art Unit</b>  2885

SEARCHED			
Class	Subclass	Date	Examiner
362	365	9/25/2007	DJM
362	453	3/20/2008	DJM

SEARCH NOTES		
Search Notes	Date	Examiner
Search in EAST attached	9/25/2007	DJM
362/147,148,150	9/25/2007	DJM
Updated search in EAST attached	3/20/2008	DJM
Inventor name search	3/20/2008	DJM
Assignee search	3/20/2008	DJM
Relevant forward/backward citation search	3/20/2008	DJM
362/147,148,150	3/20/2008	DJM
Updated search in EAST	12/19/2008	DJM
Consulted with Jacob Choi regarding potential Allowable subject matter	12/19/2008	DJM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--